## Application/Control No. Applicant(s)/Patent Under Reexamination -10/539,662 OGAWA ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 3734 Diane Yabut **U.S. PATENT DOCUMENTS Document Number** Date Classification Name Country Code-Number-Kind Code MM-YYYY 606/108 01-2000 Ken et al. US-6,013,084 Α \* 02-2004 Wilson et al. 606/108 US-2004/0034363 В \* US-2004/0002732 01-2004 Teoh et al. 606/200 С US-D US-Ε US-F US-G USн US-1 US-J US-Κ US-US-М FOREIGN PATENT DOCUMENTS Document Number Date Country Name Classification Country Code-Number-Kind Code MM-YYYY N 0 Р Q R s Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U

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